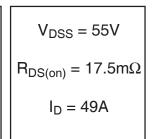
International Rectifier

R Rectifier IRFZ44NPbF

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

G



Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	49	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	35	A
I _{DM}	Pulsed Drain Current ①	160	
P _D @T _C = 25°C	Power Dissipation	94	W
	Linear Derating Factor	0.63	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current①	25	А
E _{AR}	Repetitive Avalanche Energy ^①	9.4	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.5	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

IRFZ44NPbF

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.058		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			17.5	mΩ	V _{GS} = 10V, I _D = 25A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
9fs	Forward Transconductance	19			S	V _{DS} = 25V, I _D = 25A⊕
I _{DSS}	Drain-to-Source Leakage Current			25	μA	$V_{DS} = 55V, V_{GS} = 0V$
צפטי	Brain to Gource Leakage Guiterit			250	μΛ	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100	''^	V _{GS} = -20V
Q _g	Total Gate Charge			63		I _D = 25A
Q _{gs}	Gate-to-Source Charge			14	nC	$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			23		V_{GS} = 10V, See Fig. 6 and 13
t _{d(on)}	Turn-On Delay Time		12			V _{DD} = 28V
t _r	Rise Time		60		ns	$I_D = 25A$
t _{d(off)}	Turn-Off Delay Time		44		1115	$R_G = 12\Omega$
t _f	Fall Time		45			V _{GS} = 10V, See Fig. 10 ⊕
L _D	Internal Drain Inductance		4.5			Between lead,
L-D	internal Dialit Inductance		4.5		nH	6mm (0.25in.)
	Internal Source Inductance		7.5			from package
L _S	internal Source inductance		7.5			and center of die contact
C _{iss}	Input Capacitance		1470			V _{GS} = 0V
Coss	Output Capacitance		360			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		88		pF	f = 1.0MHz, See Fig. 5
E _{AS}	Single Pulse Avalanche Energy ②		530⑤	150©	mJ	I _{AS} = 25A, L = 0.47mH

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions			
Is	Continuous Source Current			49		MOSFET symbol			
	(Body Diode)		49	A	showing the				
I _{SM}	Pulsed Source Current			- 1/		160	400		integral reverse
	(Body Diode)①			160		p-n junction diode.			
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 25A, V_{GS} = 0V \textcircled{4}$			
t _{rr}	Reverse Recovery Time		63	95	ns	$T_J = 25^{\circ}C, I_F = 25A$			
Q _{rr}	Reverse Recovery Charge		170	260	nC	di/dt = 100A/µs ④			
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L_S+L_D)							

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- $\label{eq:tau} \begin{array}{ll} \textcircled{2} & \text{Starting T}_J = 25^\circ\text{C}, \, L = 0.48\text{mH} \\ & \text{R}_G = 25\Omega, \, \text{I}_{AS} = 25\text{A}. \, \, \text{(See Figure 12)} \end{array}$
- $\label{eq:loss} \begin{array}{l} \mbox{\Large \ \, J}_{SD} \leq 25A, \; di/dt \leq 230A/\mu s, \; V_{DD} \leq V_{(BR)DSS}, \\ \mbox{\Large \ \, } T_J \leq 175^{\circ} \mbox{\Large C} \end{array}$
- $\ \, \mbox{ } \mbox$
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- $\mbox{\fontfamily{\cite{limited}}}$ This is a calculated value limited to $T_J=175^{\circ}\mbox{\cite{C}}$.

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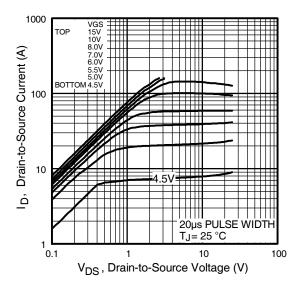


Fig 1. Typical Output Characteristics

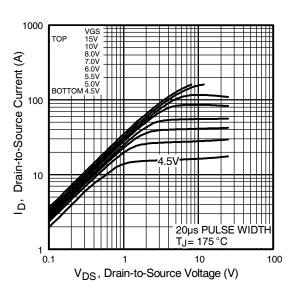


Fig 2. Typical Output Characteristics

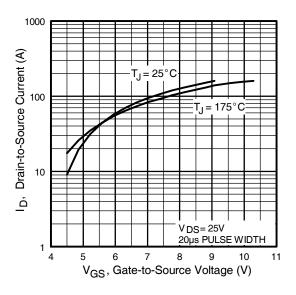


Fig 3. Typical Transfer Characteristics

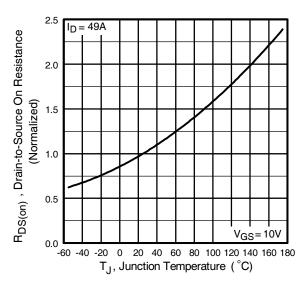


Fig 4. Normalized On-Resistance Vs. Temperature

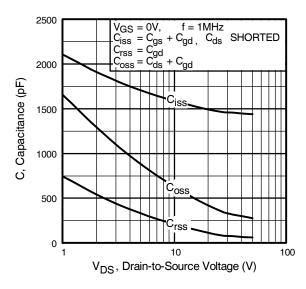
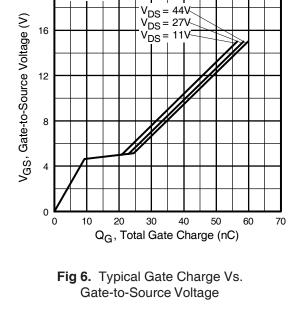


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage



ID = 25A

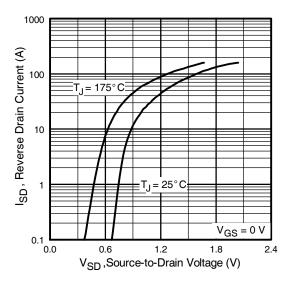


Fig 7. Typical Source-Drain Diode Forward Voltage

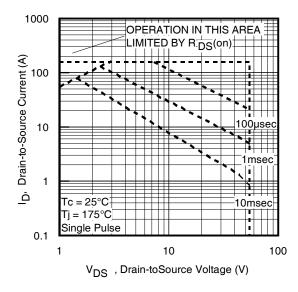


Fig 8. Maximum Safe Operating Area

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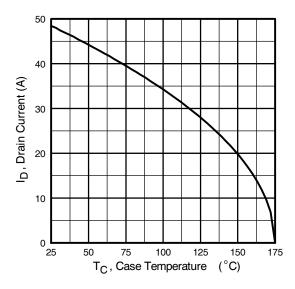


Fig 9. Maximum Drain Current Vs. Case Temperature

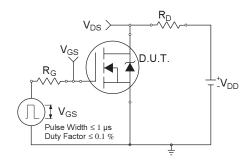


Fig 10a. Switching Time Test Circuit

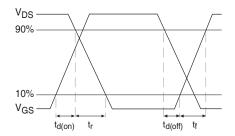


Fig 10b. Switching Time Waveforms

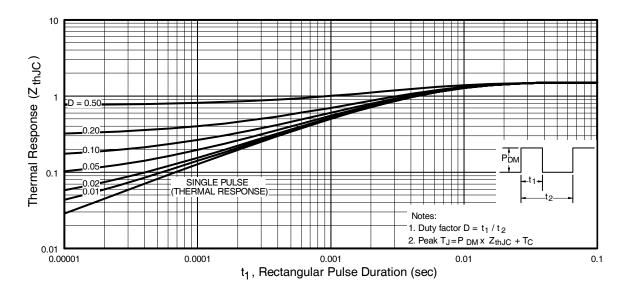


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

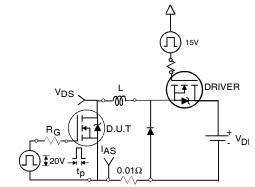


Fig 12a. Unclamped Inductive Test Circuit

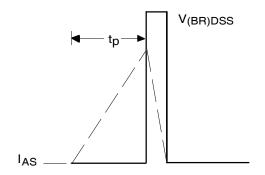


Fig 12b. Unclamped Inductive Waveforms

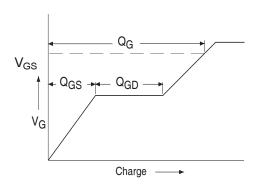


Fig 13a. Basic Gate Charge Waveform

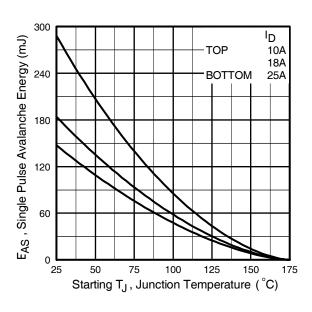


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

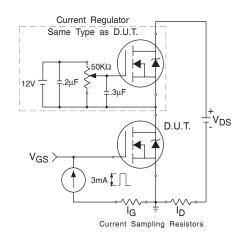
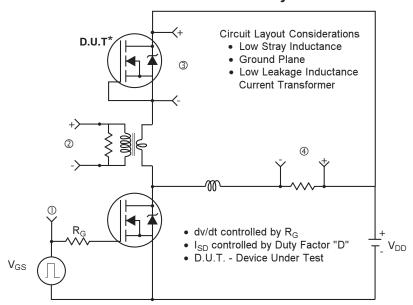


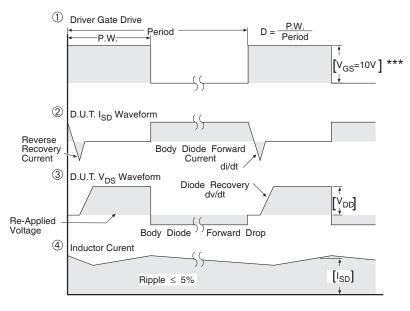
Fig 13b. Gate Charge Test Circuit

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Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



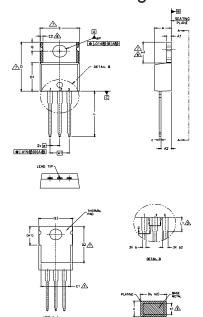
*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

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TO-220AB Package Outline (Dimensions are shown in millimeters (inches))



	NOTES	;
	1	DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.
	2	DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].
	3	LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.
	4	DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH
		SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE
	Λ	MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY,
,	∕5.→	DIMENSION 61, 63 & cf APPLY TO BASE METAL ONLY.
	6	CONTROLLING DIMENSION: INCHES.
	7	THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
	8	DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING
		AND SINGULATION IRREGULARITIES ARE ALLOWED.
	9	OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (mox.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

	DIMENSIONS					
SYMBOL	MILLIM	ETERS	INC			
	MIN.	MAX.	MIN.	MAX.	NOTES	
Α	3.56	4.83	.140	.190		
A1	0.51	1,40	.020	.055		
A2	2.03	2.92	.080	.115		
b	0.38	1.01	.015	.040		
ь1	0.38	0.97	.015	.038	5	
b2	1.14	1.78	.045	.070		
b3	1,14	1,73	.045	.068	5	
c	0.36	0.61	.014	.024		
c1	0.36	0.56	.014	.022	5	
D	14.22	16.51	.560	.650	4	
D1	8,38	9.02	.330	.355		
D2	11,68	12.88	.460	.507	7	
E	9,65	10.67	.380	.420	4,7	
E1	6,86	8.89	.270	.350	7	
E2	-	0.76	-	.030	8	
e	2.54	BSC	.100	.100 BSC		
e1	5.08	BSC	.200 BSC			
H1	5.84	6.86	.230	.270	7,8	
L	12.70	14.73	.500	.580		
L1	-	6.35	-	.250	3	
øΡ	3.54	4.08	.139	.161		
Q	2.54	3.42	.100	.135		

HEXPET

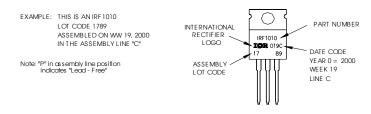
1. - GATE
2. - DRAIN
3. - SOURCE

IGBTs. COPACK
1. - GATE
2. - COLLECTOR
3. - EMITTER

DIODES

1.- ANODE/OPEN
2 - CATHODE
3.- ANODE

TO-220AB Part Marking Information



Notes:

- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market.

Qualification Standards can be found on IR's Web site.



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